FCC TEST REPORT

FCC ID : VL4-MAX-1X42W

Applicant : **DONGGUAN HOPESTAR ELECTRONIC CO., LTD.**

SANJIANG INDUSTRIAL PARK HENGLI TOWN DONGGUAN

GUANGDONG 523000 CHINA

Equipment Under Test (EUT):

Product description : FLUORESCENT ELECTRONIC BALLAST

Model No. : LEB-104~113, LEB-114~118, LEB-119~122, LEB-123~127,

LEB-128~132, LEB-133~136, LEB-137~142

Standards : FCC Part 18

Date of Test : Sep. 4, 2007

Test Engineer : Tiger Su

Reviewed By: The 2h out

PERPARED BY:

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3 Test Summary

Test	Test Requirement	Test Method	Class / Severity	Result
Radiated Emission (30MHz to 1GHz)	FCC PART 18: 2003	ANSI C63.4:2003	Class B	N/A
Conducted Emission (150KHz to 30MHz)	FCC PART 18: 2003	ANSI C63.4:2003	Class B	PASS

4 General Information

4.1 Client Information

Applicant: DONGGUAN HOPESTAR ELECTRONIC CO., LTD.

Address of Applicant: SANJIANG INDUSTRIAL PARK HENGLI TOWN

DONGGUAN, GUANGDONG 523000 CHINA

FCC ID: VL4-MAX-1X42W

4.2 General Description of E.U.T.

Product description: FLUORESCENT ELECTRONIC BALLAST

Model No.: LEB-104~113, LEB-114~118, LEB-119~122, LEB-123~127,

LEB-128~132, LEB-133~136, LEB-137~142

4.3 Details of E.U.T.

Power Supply: 120VAC / 60Hz

4.4 Description of Support Units

The EUT has been tested as an independent unit.

4.5 Standards Applicable for Testing

The customer requested FCC tests for a FLUORESCENT ELECTRONIC BALLAST. The standards used were FCC Part18.

4.6 Test Methodology

All measurements contained in this report are conducted with FCC Measurement Procedure MP-5, technical requirements for Methods of Measurement of Radio-Noise Emission from ISM Equipment.

4.7 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

• FCC – Registration No.: 759397

Solid Industrial (Shenzhen) Co., Ltd. EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration 759397, December 28, 2006.

FCC ID: VL4-MAX-1X42W

4.8 Test Location

All Emissions testswere performed at:-

Solid Industrial (Shenzhen) Co., Ltd. at 333 Bulong Highway Buji Longgang, Shenzhen, Guangdong, China.

5 Equipment Used during Test

	Conducted Emission Test								
Item	Test Equipment	Manufacturer	Model No.	Series No.	Last Cal.				
1	EMI Test Receiver	R&S	ESS	100038	2007-8				
2	LISN	Kyoritsu	KNW-403D	N/A	2007-8				
3	Pulse Limiter	R&S	ESHSZ2	100044	2007-8				

FCC ID: VL4-MAX-1X42W

6 Conducted Emission Test

Product Name: FLUORESCENT ELECTRONIC BALLAST

Test Requirement: FCC Part 18

Test Method: Based on FCC Part 18

Test Date: Sep.4, 2007

Frequency Range: 150kHz to 30MHz

Class B

Detector: Peak for pre-scan (9kHz Resolution Bandwidth)

Quasi-Peak & Average if maximised peak within 6dB of

FCC ID: VL4-MAX-1X42W

Average Limit

6.1 Test Equipment

Please refer to Section 5 this report.

6.2 Test Procedure

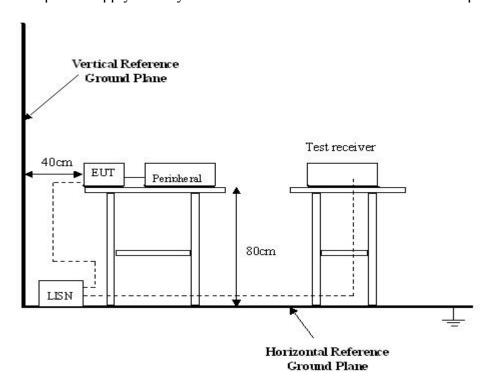
- 1. During the conducted emission test, the power cord of the EUT is connected to the auxiliary outlet of the LISN.
- 2. The EUT was tested according to FCC MP-5. The frequency spectrum from 150kHz to 30MHz was investigated.
- 3. The maximised peak emissions from the EUT was scanned and measured for both the Live and Neutral Lines. Quasi-peak & average measurements were performed if peak emissions were within 6dB of the average limit line.

6.3 Conducted Test Setup

The conducted emission tests were performed using the setup accordance with the FCC MP-5 measurement procedure.

The EUT is tested independently.

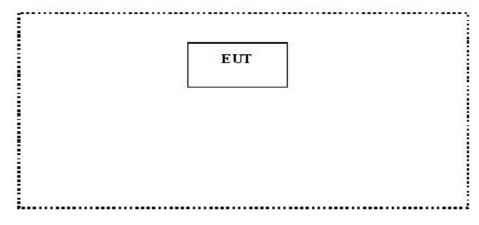
The power supply used by the EUT is connected to a $120VAC\ / \ 60Hz$ power source.



6.4 EUT Operating Condition

Operating condition is according to FCC MP-5.

- A. Setup the EUT and simulators as shown on follow.
- B. Enable RF signal and confirm EUT active.
- C. Modulate output capacity of EUT up to specification.



6.5 Conducted Emission Limits

Frequency of Emission	Conducted Limit (dBuV)- Quasi-peak
(MHz)	
0.15— 0.5	66-56
0.5 — 5.0	56
5.0 — 30	60

Note: In the above limits, the tighter limit applies at the band edges.

6.6 Spectrum Analyzer

The spectrum analyzer is configured during the conduction test is as follows:

Start Frequency 150 kHz
Stop Frequency 30 MHz
Sweep SpeedAuto
IF Bandwidth 9 kHz
$Video\ Bandwidth \cdots \cdots 100\ kHz$
Quasi-Peak Adaptor Bandwidth9 kHz
Quasi-Peak Adaptor Mode·····Normal

6.7 Frequency Range Of Measurements

Frequency band in	Range of frequency measurements					
which device operates (MHz)	Lowest frequency	Highest frequency				
Below 1.705	Lowest frequency generated in the	30MHz.				
	device, but not lower than 9 kHz.					
1.705 to 30	Lowest frequency generated in the	400MHz.				
	device, but not lower than 9 kHz.					
30 to 500	Lowest frequency generated in the	Tenth harmonic or				
	device or 25MHz, whichever is	1,000MHz, whichever is				
	lower.	higher.				
500 to 1,000	Lowest frequency generated in the	Tenth harmonic.				
	device or 100MHz, whichever is					
	lower.					
Above 1,000	do	Tenth harmonic or highest				
		detectable emission.				

6.8 Conducted Emission Test Result

Test Item: Conducted Emission Test

Test Voltage: 120VAC / 60Hz

Test Mode: Normal
Temperature: 24 °C
Humidity: 52%RH
Test Result: PASS

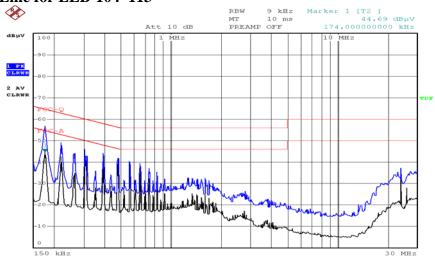
6.8.1 Measurement Data

An initial pre-scan was performed on the live and neutral lines.

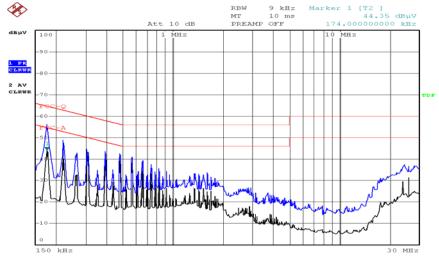
No futher quasi-peak or average measurements were performed since no peak emissions were detected within 10dB line below the average limit.

Please refer to the following peak scan graph for reference.

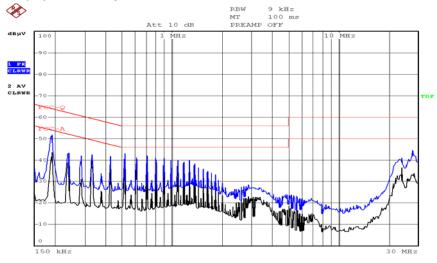
Live Line for LEB-104~113



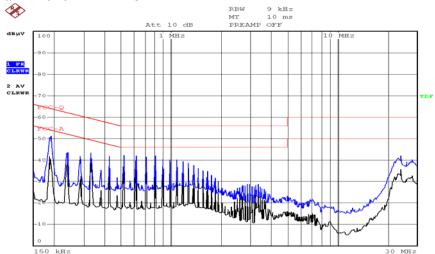
Neutral Line for LEB-104~113



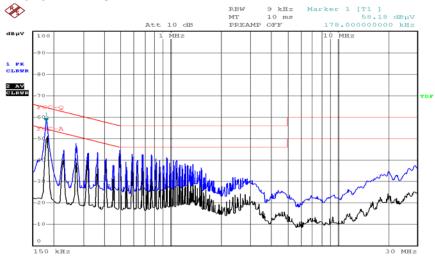
Live Line for LEB-123~127



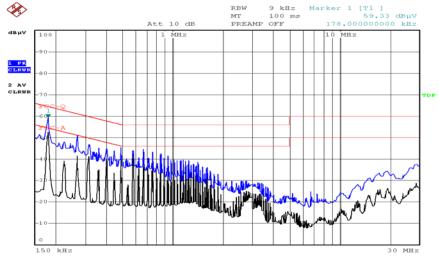
Neutral Line for LEB-123~127



Live Line for LEB-137~142



Neutral Line for LEB-137~142



Conducted Test Data Live Line for LEB-104~113

NO	Frequency	QP Level	AV Level	QP Limit	AV Limit	QP margin	AV margin
NO.	[MHz]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]
1	0.170	57.2	44.6	64.9	54.9	7.7	10.3
2	0.220	49.1	43.1	62.8	52.8	13.7	9.7
3	0.300	46.3	40.2	60.2	50.2	13.9	10.0
4	0.481	42.8	39.3	56.4	46.4	13.6	7.1
5	0.562	40.5	35.6	56.0	46.0	15.5	10.4

Conducted Test Data Neutral Line for LEB-104~113

NO.	Frequency	QP Level	AV Level	QP Limit	AV Limit	QP margin	AV margin
NO.	[MHz]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]
1	0.170	56.6	44.3	64.9	54.9	8.3	10.6
2	0.225	48.2	41.2	62.6	52.6	14.4	11.4
3	0.300	44.9	40.1	60.2	50.2	15.3	10.1
4	0.480	43.2	39.4	56.4	46.4	13.2	7.0
5	0.578	42.0	37.6	56.0	46.0	14.0	8.4

Conducted Test Data Live Line for LEB-123~127

NO	Frequency	QP Level	AV Level	QP Limit	AV Limit	QP margin	AV margin
NO.	[MHz]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]
1	0.186	52.3	44.5	64.2	54.2	11.9	9.7
2	0.250	44.4	38.0	61.8	51.8	17.4	13.8
3	0.336	44.2	39.1	59.3	49.3	15.1	10.2
4	0.425	44.1	36.5	57.4	47.4	13.3	10.9

Conducted Test Data for Neutral Line LEB-123~127

NO	Frequency	QP Level	AV Level	QP Limit	AV Limit	QP margin	AV margin
NO.	[MHz]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]
1	0.188	52.0	43.1	64.1	54.1	12.1	11.0
2	0.247	44.7	38.4	61.8	51.8	17.1	13.4
3	0.339	44.3	37.0	59.3	49.3	15.0	12.3
4	0.427	43.5	35.5	57.4	47.4	13.9	11.9

Conducted Test Data Live Line for LEB-137~142

NO	Frequency	QP Level	AV Level	QP Limit	AV Limit	QP margin	AV margin
NO.	[MHz]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]
1	0.178	58.1	50.2	64.6	54.6	6.5	4.4
2	0.247	47.7	41.1	61.9	51.9	14.2	10.8
3	0.354	44.2	38.4	58.9	48.9	14.7	10.5
4	0.497	45.1	37.2	56.1	46.1	11.0	8.9

Conducted Test Data for Neutral Line LEB-137~142

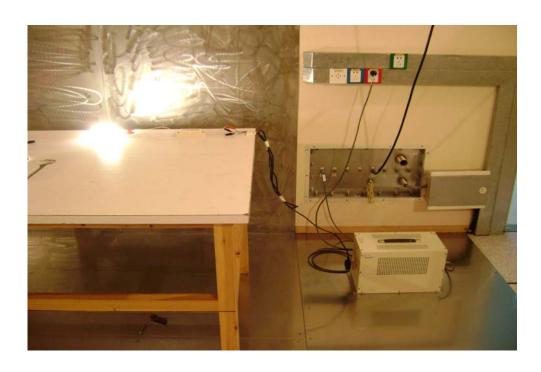
NO	Frequency	QP Level	AV Level	QP Limit	AV Limit	QP margin	AV margin
NO.	[MHz]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]
1	0.163	59.3	43.2	65.3	55.3	6.0	12.1
2	0.244	51.9	42.2	61.9	51.9	10.0	9.7
3	0.321	46.1	41.8	59.7	49.7	13.6	7.9
4	0.400	44.2	40.0	57.9	47.9	13.7	7.9

Photographs of Testing 7

Conducted Emission Test View for LEB-104~113 7.1



Conducted Emission Test View for LEB-123~127 7.2



7.3 Conducted Emission Test View for LEB-137~142



8 Photographs-Constructional Details

8.1 EUT-Front View for LEB-104~113



8.2 EUT-Back View for LEB-104~113



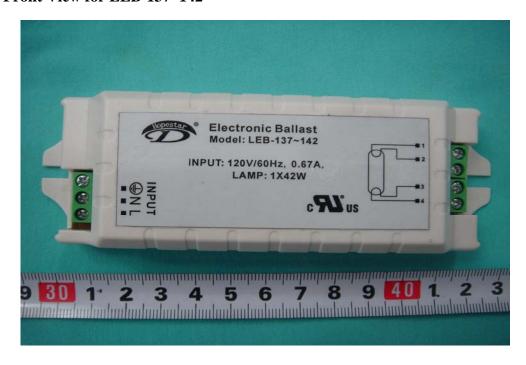
8.3 EUT-Front View for LEB-123~127



8.4 EUT-Back View for LEB-123~127



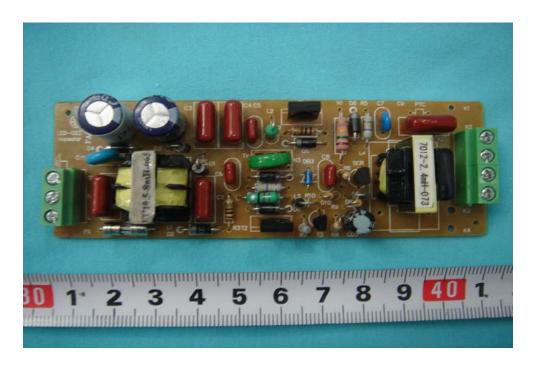
8.5 EUT-Front View for LEB-137~142



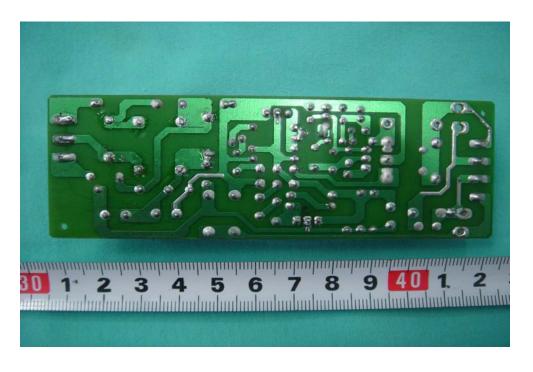
8.6 EUT-Back View for LEB-137~142



PCB-Front View for LEB-104~113



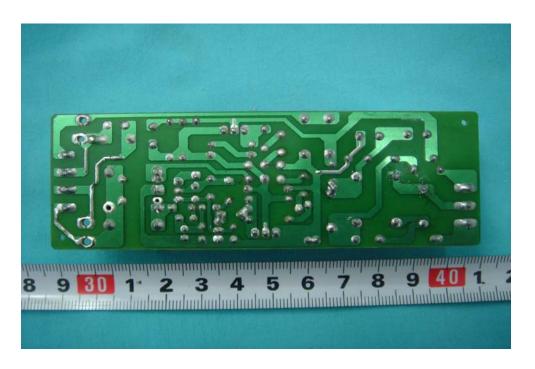
8.8 PCB-Back View for LEB-104~113



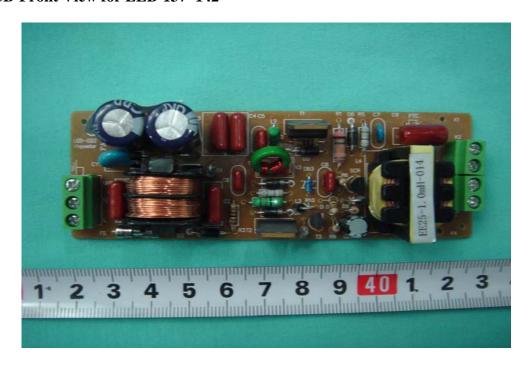
PCB-Front View for LEB-123~127



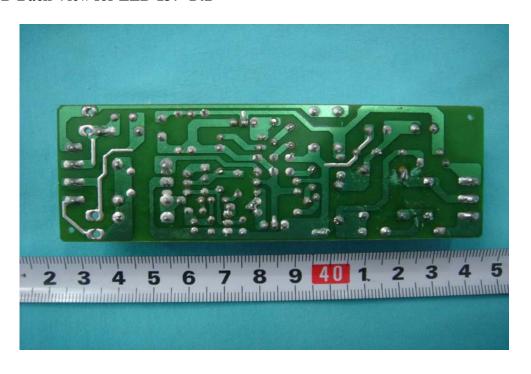
8.10 PCB-Back View for LEB-123~127



8.11 PCB-Front View for LEB-137~142



8.12 PCB-Back View for LEB-137~142

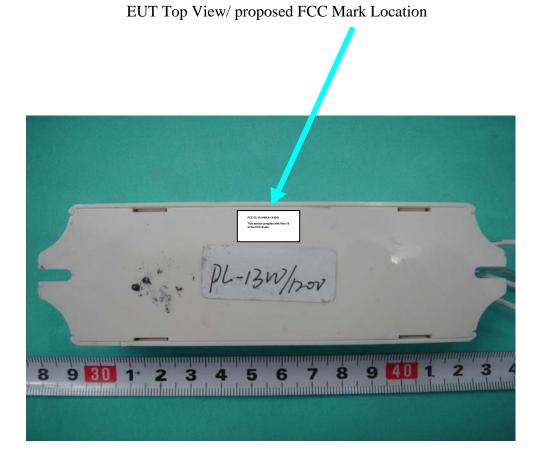


9 FCC ID Label

This device complies with Part 18 of the FCC Rules. Operation is subject to the following two conditions:(1)this device may not cause harmful interference,and (2) this device must accept any interference received, including interference that may cause undesired operation.

The Label must not be a stick-on paper. The Label on these products must be permanently affixed to the product and readily visible at the time of purchase and must last the expected lifetime of the equipment not be readily detachable.

Proposed Label Location on EUT



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